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System-level Test and Validation of Hardware/Software Systems

With 55 Figures

 Springer

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Table of Contents

Table of Figures	ix
List of Contributors	xi
1 Introduction	
<i>Z. Peng, M. Sonza Reorda and M. Violante</i>	1
Acknowledgments	3
2 Modeling Permanent Faults	
<i>J.P. Teixeira</i>	5
2.1 Abstract	5
2.2 Introduction	5
2.3 Definitions	8
2.4 High-level Quality Metrics	9
2.5 System and Register-transfer-level Fault Models for Permanent Faults	12
2.5.1 Observability-based Code Coverage Metrics	15
2.5.2 Validation Vector Grade	15
2.5.3 Implicit Functionality, Multiple Branch	17
2.6 Conclusions	22
Acknowledgments	23
References	23
3 Test Generation: A Symbolic Approach	
<i>F. Fummi and G. Pravadelli</i>	27
3.1 Abstract	27
3.2 Introduction	27
3.3 Binary Decision Diagrams	29
3.4 Methodology	30
3.4.1 The Random-based Approach	31
3.4.2 The Symbolic Approach	31
3.4.3 Hardware Design Language to Binary Decision Diagram Translation	32
3.4.4 Functional Vector Generation for a Single Process	32
3.4.5 Functional Vector Generation for Interconnected Processes	33
3.5 The Testing Framework	33
3.5.1 Fault Model Definition	35
3.5.2 Automatic Test Pattern Generation Engines	41
3.6 Experimental Results	43
3.7 Concluding Remarks	44
Acknowledgments	45
References	45

4 Test Generation: A Heuristic Approach

<i>O. Goloubeva, M. Sonza Reorda and M. Violante</i>	47
4.1 Abstract	47
4.2 Introduction.....	47
4.3 Assumptions.....	50
4.4 High-level Test Generation	50
4.4.1 High-level Fault Models	50
4.4.2 High-level Test Generation.....	51
4.5 Testing Hardware/Software Systems	52
4.5.1 testgen Results	54
4.5.2 Results Starting from Random Vectors.....	55
4.5.3 Results Starting from Designer Vectors.....	55
4.5.4 Result Discussion.....	56
4.6 Validating Application-specific Processors	56
4.6.1 Design Flow	58
4.6.2 Experimental Results	60
4.6.3 Results of the Processor Customization.....	61
4.6.4 Results of the Test Vector Generation	61
4.7 Conclusions.....	63
References.....	64

5 Test Generation: A Hierarchical Approach

<i>G. Jervan, R. Ubar, Z. Peng and P. Eles</i>	67
5.1 Abstract	67
5.2 Introduction.....	67
5.3 Modeling with Decision Diagrams	68
5.3.1 State of the Art	68
5.3.2 Modeling Digital Systems by Binary Decision Diagrams	69
5.3.3 Modeling with a Single Decision Diagram on Higher Levels	71
5.4 Hierarchical Test Generation with Decision Diagrams.....	73
5.4.1 Scanning Test.....	74
5.4.2 Conformity Test.....	78
5.5 Conclusions.....	80
References.....	81

6 Test Program Generation from High-level Microprocessor Descriptions

<i>E. Sánchez, M. Sonza Reorda and G. Squillero</i>	83
6.1 Abstract	83
6.2 Introduction.....	83
6.3 Microprocessor Test-program Generation	85
6.4 Methodology Description.....	87
6.4.1 Architectural Models	89
6.4.2 Register-transfer-level Models.....	90
6.5 Case Study	94
6.5.1 Processor Description	94
6.5.2 Automatic Tool Description.....	96

6.5.3	Experimental Setup	98
6.6	Experimental Results	99
6.6.1	High-level Metrics Comparison	103
6.7	Conclusions	104
	Acknowledgments.....	105
	References.....	105
7	Tackling Concurrency and Timing Problems	
	<i>I.G. Harris</i>	107
7.1	Abstract	107
7.2	Introduction.....	107
7.3	Synchronization Techniques	109
7.4	A Class of Synchronization Errors.....	111
7.5	A Fault Model for Synchronization Errors.....	113
7.5.1	Detection of Synchronization Faults	114
7.5.2	Fault Coverage Computation	115
7.6	Experimental Results	116
7.7	Conclusions	118
	Acknowledgments.....	118
	References.....	118
8	An Approach to System-level Design for Test	
	<i>G. Jervan, R. Ubar, Z. Peng and P. Eles</i>	121
8.1	Abstract	121
8.2	Introduction.....	121
8.3	Hybrid Built-in Self-test.....	123
8.3.1	Hybrid Built-in Self-test Cost Optimization	126
8.4	Hybrid Built-in Self-test for Multi-core Systems.....	129
8.4.1	Built-in Self-test Time Minimization for Systems with Independent Built-in Self-test Resources	130
8.4.2	Built-in Self-test Time Minimization for Systems with Test Pattern Broadcasting	139
8.5	Conclusions.....	146
	References.....	147
9	System-level Dependability Analysis	
	<i>A. Bobbio, D. Codetta Raiteri, M. De Pierro and G. Francheschinis</i>	151
9.1	Abstract	151
9.2	Introduction.....	151
9.3	Introduction to Fault Trees.....	153
9.3.1	Fault Tree Example	154
9.3.2	Modeling Dependencies in the Failure Mode Using Dynamic Gates.....	155
9.3.3	Giving a Compact Representation of Symmetric Systems through Parameterization	156
9.3.4	Modeling the Repair Process Through the Repair Box.....	158

9.4 Reliability Analysis.....	159
9.4.1 Qualitative Analysis.....	159
9.4.2 Quantitative Analysis.....	160
9.4.3 Importance Measures.....	161
9.5 Qualitative and Quantitative Analysis of the Examples.....	163
9.5.1 Minimal Cut-sets Detection.....	163
9.5.2 Quantitative Analysis.....	164
9.6 Conclusions.....	171
Acknowledgments.....	172
References.....	172
Index	175

Table of Figures

Figure 2.1. Test objectives	7
Figure 2.2. Representativeness of RTL, gate-level LSA faults and physical defects	18
Figure 2.3. Typical RTL fault detectability profile	21
Figure 2.4. Typical DC improvement, using IFMB	22
Figure 3.1. HTD and ETD errors for a GA-based and a BDD-based ATPG	29
Figure 3.2. A BDD for function $f(v_1, v_2, v_3, v_4) = v_1 v_2 v_3 + \bar{v}_1 v_4 + \bar{v}_2 v_4$	30
Figure 3.3. Laerte++ setup flow	34
Figure 3.4. Laerte++ testbench	35
Figure 3.5. Fault hierarchy	36
Figure 3.6. TransientFault class definition	36
Figure 3.7. Saboteur VHDL function for bit operands	39
Figure 3.9. Saboteur VHDL function for integer operands	39
Figure 3.8. Saboteur VHDL function for bit vector operands	40
Figure 3.10. Fault-free and generated faulty VHDL code	40
Figure 3.11. Sequence hierarchy	41
Figure 3.12. A new sequence class definition	43
Figure 4.1. The pseudo-code of the HLTG algorithm	52
Figure 4.2. Simulation of testgen vectors	54
Figure 4.3. Simulation of HLTG vectors	54
Figure 4.4. The proposed processor customization and validation flow	60
Figure 5.1. A gate-level circuit and its corresponding SSBDD	71
Figure 5.2. Representing a data path by a DD	72
Figure 5.3. DIFFEQ benchmark with testability figures for every individual FU	77
Figure 5.4. Conformity test example	79
Figure 6.1. Qualitative description of the methodology	88
Figure 6.2. Architectural models stage	90
Figure 6.3. RT model stage	91
Figure 6.4. PLASMA block diagram	95
Figure 6.5. μ GP general architecture	97
Figure 7.1. Synchronization in a producer/consumer example	112
Figure 7.2. Two types of MTE fault	114
Figure 7.3. AAL1 MTE fault coverage distribution	118
Figure 7.4. AAL MTE coverage without the rec_seq signal	118
Figure 8.1. Cost calculation for hybrid BIST (under 100% assumption)	124
Figure 8.2. Cost calculation for hybrid BIST	125
Figure 8.3. An example of a core-based system, with independent BIST resources	130
Figure 8.4. <i>Ad hoc</i> test schedule for hybrid BIST of the core-based system example	131
Figure 8.5. Estimation of the length of the deterministic test sequence	134

Figure 8.6. Estimation of the length of the deterministic test sequence (core s1423)	135
Figure 8.7. Cost curves for a given core C_k	136
Figure 8.8. Minimization of the test length.....	137
Figure 8.9. The final test solution for the system S2 ($M_{LIMIT} = 5500$)	138
Figure 8.11. A core-based system example with the proposed test architecture	139
Figure 8.12. Hybrid test set example	141
Figure 8.13. Iterative cost estimation.....	145
Figure 8.14. Final hybrid test structure.....	146
Figure 8.15. Comparison of estimated and real test costs	147
Figure 9.1. The FT for the storage system with hot spare memories	154
Figure 9.2. State-space representation of the dependency of spare S on main component M	156
Figure 9.3. The DFT for the system with warm spares.....	157
Figure 9.4. (a) DPFT and (b) RDPFT for the system with warm spares.....	158
Figure 9.5. The MIF values for the components of the system with hot spares.	166
Figure 9.6. The SWN corresponding to the dynamic module whose root is the event SET	167
Figure 9.7. The unreliability values for all the system configurations.....	170

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